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Application/Control No.	Applicant(s)/Patent und Reexamination	ər
10/630,775	KAMON, KAZUYA	
Examiner	Art Unit	
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Class	Subclass	Date	Examiner
703	013	4/12/2006	APL
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INTERFERENCE SEARCHED			
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SEARCH NOT (INCLUDING SEARCH)
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EAST (EAST (US- PGPUB;USPAT;USOCR;EPO;JPO;D ERWENT;IBM_TDB)- SEE ATTACHMENT	2/23/2006	APL
EAST (EAST (US- PGPUB;USPAT;USOCR;EPO;JPO;D ERWENT;IBM_TDB)- SEE ATTACHMENT	4/12/2006	APL
703/13-22 AND 716/1-21 (text search only-see search history printout)	2/23/2006	APL
INVENTOR NAME SEARCH	4/12/2006	APL
Above Search Updated	3/22/2007	APL